

Application/Control No.	Applicant(s)/Patent under Reexamination
10/693,898	CHI, LI-WEN
Examiner	Art Unit
Richard K. Lee	2832

					IS	SUE C	CLASSIF	FICATIO	N			-					
			ORIG	NAL		CROSS REFERENCE(S)											
CLASS SUBCLASS					CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)											
200 6R			200	4 332													
II	NTER	RNAT	IONAL (CLASSIFICATION													
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		(As	- sistant	Examiner) (D	aţe)			3	Total Claims Allowed: 1								
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	(Le	gell	nstrukt	ente Examiner)	(Date)	(P	rimary Examine	r) (D		4							

	Claims renumbered in the same order as presented by applicant											□СРА		☐ T.D.		☐ R.1.47		
Final	Original		Final	Original		Final	Original		Final	Original		Final	Original	Final	Original		Final	Original
1	1			31			61			91			121		151			181
	2			32			62			92			122		152			182
	3			33			63			93			123		153			183
	4			34			64			94			124		154			184
	5			35			65]		95			125		155			185
	6			36			66	1		96			126		156			186
	7			37			67			97			127		157			187
	8			38			68			98			128		158			188
	9			39			69			99			129		159			189
	10			40			70			100			130		160			190
	11			41			71			101			131		161			191
	12			42			72			102			132		162			192
	13			43			73			103			133		163			193
	14			44			74			104			134		164			194
	15			45			75			105			135		165			195
	16			46			76			106) ()-		136		166			196
	17			47			77			107	4		137		167			197
	18			48		1	78			108			138		168			198
	19			49			79			109			139		169			199
	20			50			80			110			140		170			200
	21			51			81			111			141		171			201
	22			52			82			112			142		172			202
	23			53			83			113			143		173			203
	24			54			84	1		114			144		174			204
	25			55			85			115			145		175			205
	26			56			86			116			146		176			206
	27			57			87			117			147		177			207
	28			58			88			118			148		178			208
	29			59			89			119			149		179			209
	30			60			90	1		120			150		180			210